

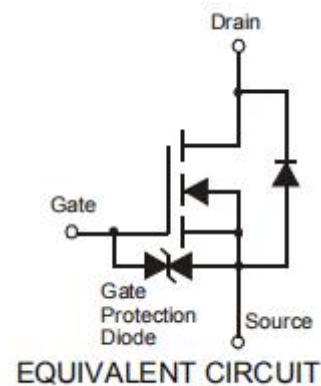
## Plastic-Encapsulate MOSFETS

### N-CHANNEL ENHANCEMENT MODE MOSFET

#### Features

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Lead Free By Design/RoHS Compliant (Note 2)
- ESD Protected up to 2kV
- Marking Code: NA1

**SOT-23**



#### Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic			Symbol	Value	Units
Drain-Source Voltage			VDSS	20	V
Gate-Source Voltage			VGSS	$\pm 6$	V
Continuous Drain Current (Note 1)	Steady State	$T_A = 25^\circ\text{C}$ $T_A = 85^\circ\text{C}$	$I_D$	0.63 0.45	A
Pulsed Drain Current			IDM	6	A

#### Thermal Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 1)		$P_D$	0.28	W
Thermal Resistance, Junction to Ambient		$R_{J\text{A}}$	452	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to +150	$^\circ\text{C}$

Notes: 1. Device mounted on FR-4 PCB.  
2. No purposefully added lead.

**Electrical Characteristics** @ $T_A = 25^\circ\text{C}$  unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 4)</b>						
Drain-Source Breakdown Voltage	BVDSS	20	-	-	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
Zero Gate Voltage Drain Current $T_J = 25^\circ\text{C}$	IDSS	-	-	100	nA	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	IGSS	-	-	$\pm 1.0$	$\mu\text{A}$	$V_{GS} = \pm 4.5\text{V}, V_{DS} = 0\text{V}$
<b>ON CHARACTERISTICS (Note 4)</b>						
Gate Threshold Voltage	$V_{GS(\text{th})}$	0.5	-	1.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	RDS (ON)	-	0.3	0.4	$\Omega$	$V_{GS} = 4.5\text{V}, I_D = 600\text{mA}$
			0.4	0.5		$V_{GS} = 2.5\text{V}, I_D = 500\text{mA}$
			0.5	0.7		$V_{GS} = 1.8\text{V}, I_D = 350\text{mA}$
Forward Transfer Admittance	$ Y_{fs} $	-	1.4	-	S	$V_{DS} = 10\text{V}, I_D = 400\text{mA}$
Diode Forward Voltage (Note 4)	VSD		0.7	1.2	V	$V_{GS} = 0\text{V}, I_S = 150\text{mA}$
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	Ciss	-	60.67	-	pF	$V_{DS} = 16\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	Coss	-	9.68	-	pF	
Reverse Transfer Capacitance	Crss	-	5.37	-	pF	
Total Gate Charge	Qg	-	736.6	-	pC	$V_{GS} = 4.5\text{V}, V_{DS} = 10\text{V}, I_D = 250\text{mA}$
Gate-Source Charge	Qgs	-	93.6	-	pC	
Gate-Drain Charge	Qgd	-	116.6	-	pC	
Turn-On Delay Time	tD(on)	-	5.1	-	ns	$V_{DD} = 10\text{V}, V_{GS} = 4.5\text{V}, R_L = 47\Omega, R_G = 10\Omega, I_D = 200\text{mA}$
Turn-On Rise Time	t <sub>r</sub>	-	7.4	-	ns	
Turn-Off Delay Time	tD(off)	-	26.7	-	ns	
Turn-Off Fall Time	t <sub>f</sub>	-	12.3	-	ns	

Notes: 4. Short duration pulse test used to minimize self-heating effect.

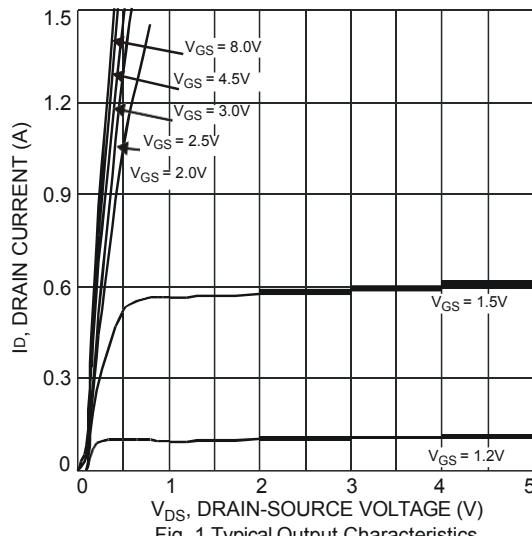


Fig. 1 Typical Output Characteristics

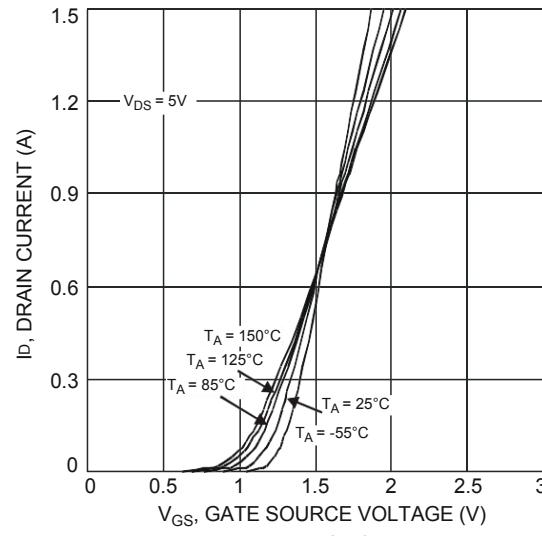
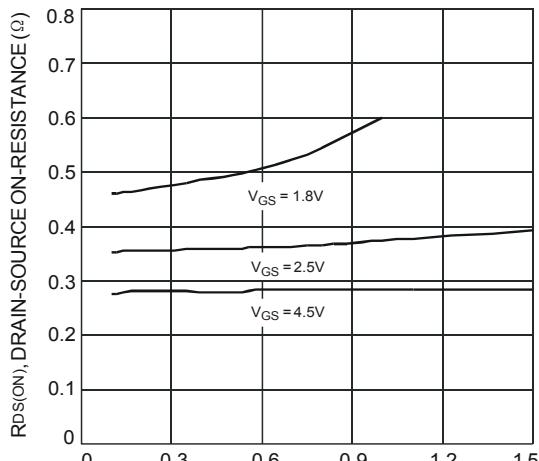


Fig. 2 Typical Transfer Characteristics



I<sub>D</sub>, DRAIN-SOURCE CURRENT (A)  
Fig. 3 Typical On-Resistance  
vs. Drain Current and Gate Voltage

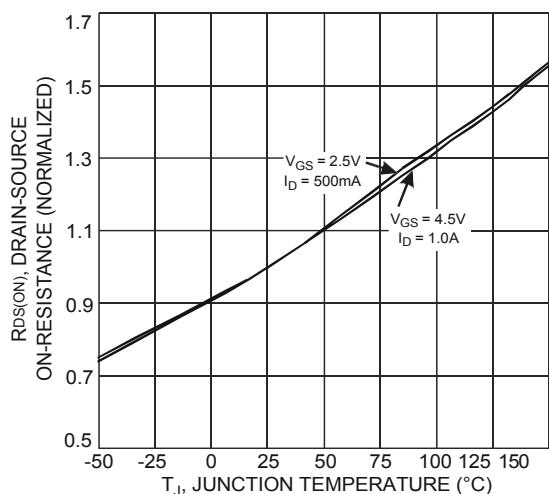


Fig. 5 On-Resistance Variation with Temperature

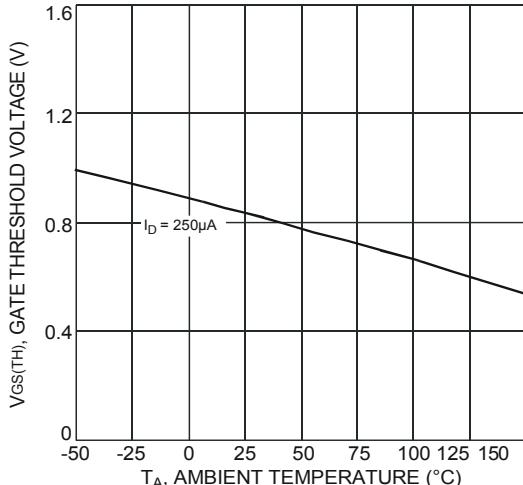
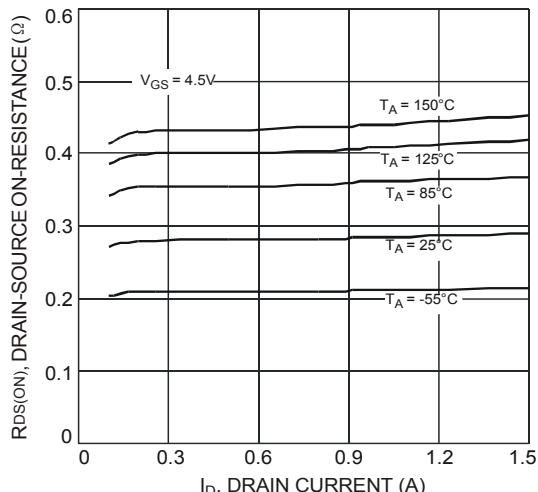


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



I<sub>D</sub>, DRAIN CURRENT (A)  
Fig. 4 Typical Drain-Source On-Resistance  
vs. Drain Current and Temperature

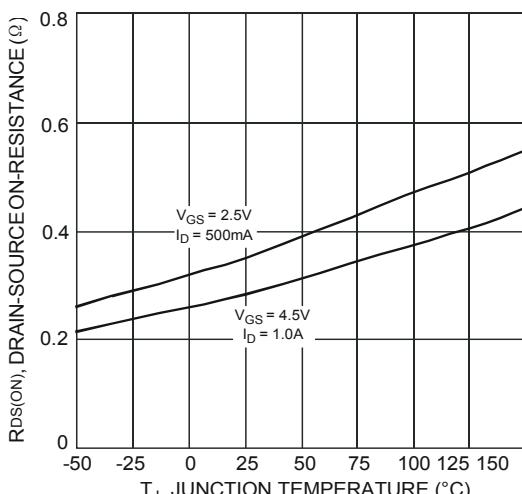


Fig. 6 On-Resistance Variation with Temperature

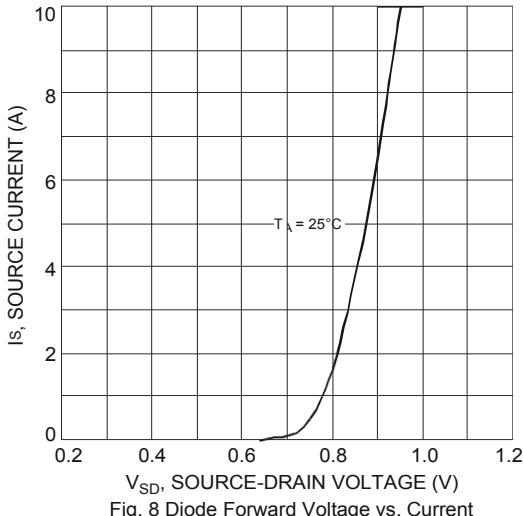


Fig. 8 Diode Forward Voltage vs. Current

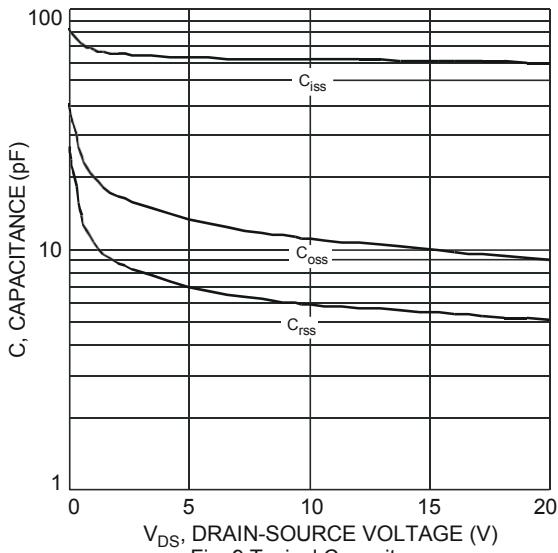


Fig. 9 Typical Capacitance

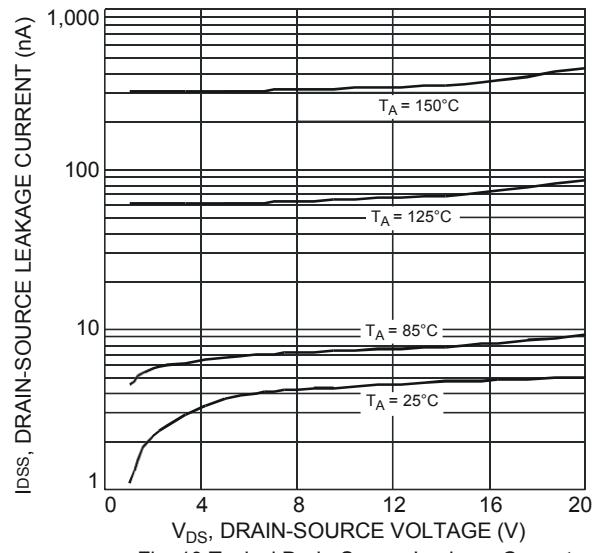


Fig. 10 Typical Drain-Source Leakage Current vs. Drain-Source Voltage

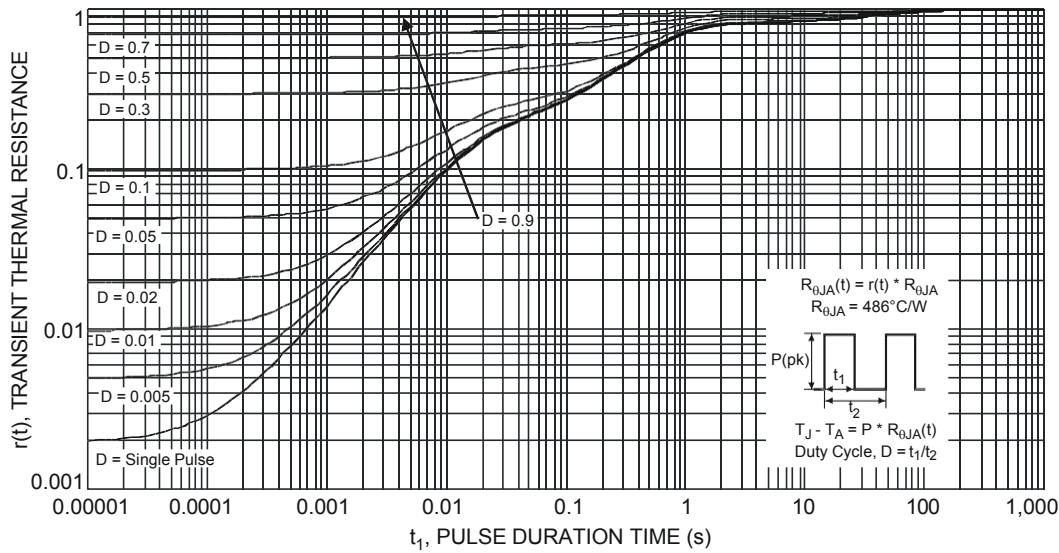


Fig. 11 Transient Thermal Response